

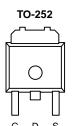
19N10L-TN3-R-VB Datasheet N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
	0.055 at V _{GS} = 10 V	25				
100	0.057 at V _{GS} = 4.5 V	25	21nC			

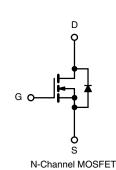
FEATURES

- Trench power MOSFET
- 100 % UIS tested





Top View



APPLICATIONS

Primary side switch

PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	100	V
Gate-Source Voltage		V _{GS}	± 20	V
	T _C = 25 °C		25	
Continuous Dunis Comment (T. 175 °C)	T _C = 70 °C		20	
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	12 b, c	
	T _A = 70 °C		10 b, c	
Pulsed Drain Current	I _{DM}	75	A	
Continuous Courses Dunis Diada Coursest	T _C = 25 °C		50 e	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	6.9 b, c	
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	33	
Single Pulse Avalanche Energy	L = U.1 IIII	E _{AS}	55	mJ
	T _C = 25 °C		83	
Manian and Danier Disable at land	T _C = 70 °C		58	w
Maximum Power Dissipation	T _A = 25 °C	P _D	8.3 b, c	VV
	T _A = 70 °C		5.8 b, c	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +175	°C

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum Junction-to-Ambient b, d	t ≤ 10 s	R_{thJA}	15	18	°C/W	
Maximum Junction-to-Case	Steady State	R_{thJC}	1.5	1.8	C/ VV	

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under steady state conditions is 50 $^{\circ}\text{C/W}.$
- e. Calculated based on maximum junction temperature. Package limitation current is 50 A.



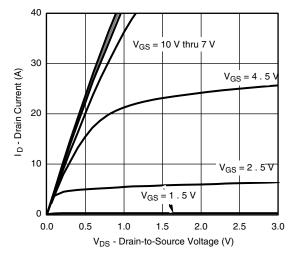
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100	=	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	165	-	mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-11	-	mv/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.0		3.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	Inno	V _{DS} = 100 V, V _{GS} = 0 V	-	- 1		μA
Zero date voltage Brain Gunem	I _{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$	-	-	10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25	-	-	Α
Drain-Source On-State Resistance a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D=12A}$	-	0.000		Ω
	· ·D3(011)	V_{GS} =4.5 V, I_D =8A		0.057		
Forward Transconductance a	g _{fs}	V _{DS} = 15 V, I _D = 12 A	-	25	-	S
Dynamic ^b						
Input Capacitance	C _{iss}		=	1800	-	pF
Output Capacitance	Coss	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	180	-	
Reverse Transfer Capacitance	C _{rss}		-	60	-	
Total Gate Charge	Qg		-	21	32	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$	-	10	-	
Gate-Drain Charge	Q _{gd}		-	9	-	
Gate Resistance	R_g	f = 1 MHz	-	1.5	-	Ω
Turn-On Delay Time	t _{d(on)}		-	10	15	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_1 = 5 \Omega$	-	10	15	ns
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10$ A, $V_{GEN} = 10$ V, $R_g = 1$ Ω	-	15	25	
Fall Time	t _f		=	10	15	
Drain-Source Body Diode Characteristic	S		L		L	
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	_	-	50	
Pulse Diode Forward Current ^a	I _{SM}		-	=	40	A
Body Diode Voltage	V_{SD}	I _S = 10 A	-	0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}		-	50	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}		-	100	150	nC
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	-	38	-	
Reverse Recovery Rise Time	t _b		_	12	_	ns

Note

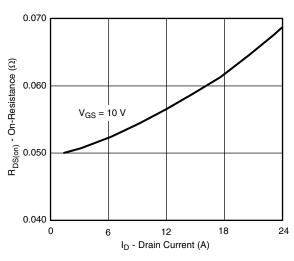
- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

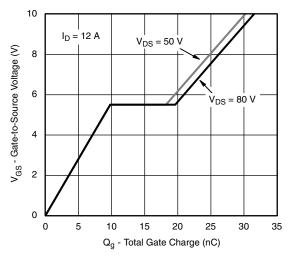




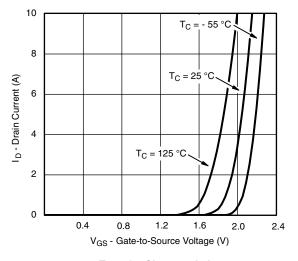




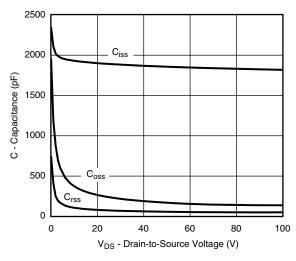
On-Resistance vs. Drain Current



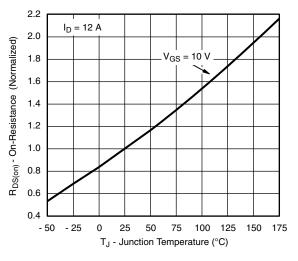
Gate Charge



Transfer Characteristics

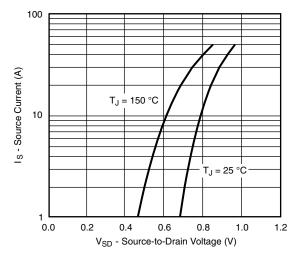


Capacitance

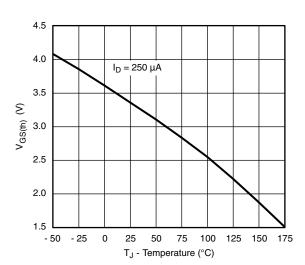


On-Resistance vs. Junction Temperature

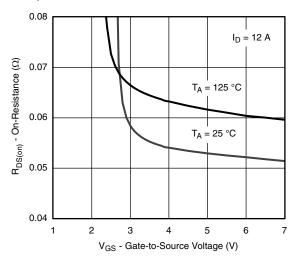




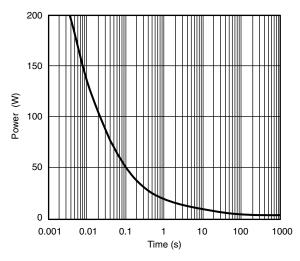
Source-Drain Diode Forward Voltage



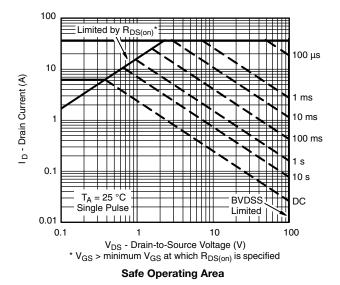
Threshold Voltage



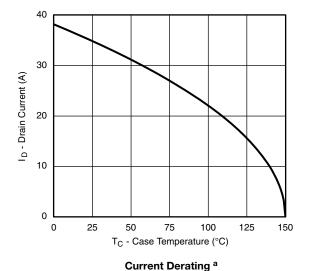
R_{DS(on)} vs. V_{GS} vs. Temperature

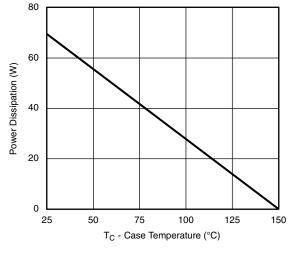


Single Pulse Power, Junction-to-Ambient







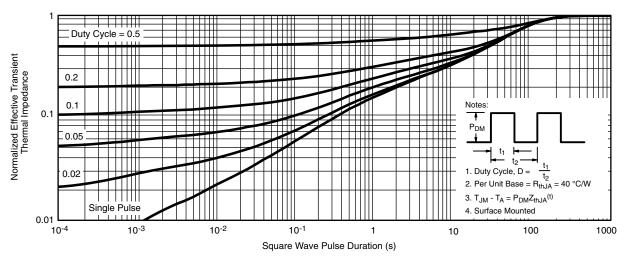


Power Derating

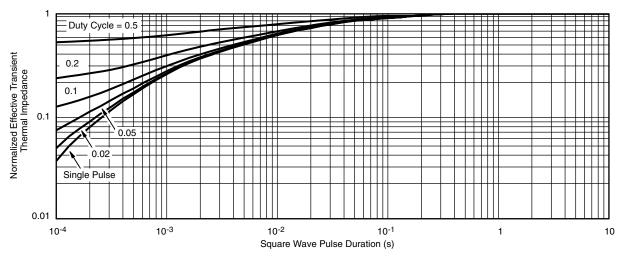
Note

a. The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





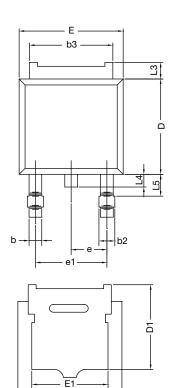
Normalized Thermal Transient Impedance, Junction-to-Ambient

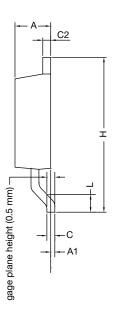


Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA Case Outline





	MILLIMETERS		INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	4.10	-	0.161	-		
E	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	BSC	0.090 BSC			
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.01	1.52	0.040	0.060		
ECN: T16-0236-Rev. P, 16-May-16						

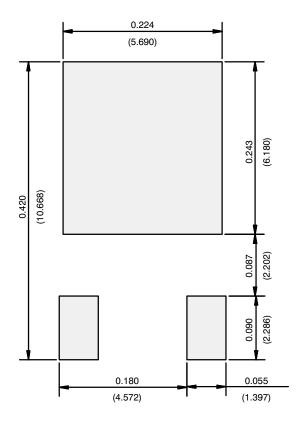
ECN: T16-0 DWG: 5347

Notes

• Dimension L3 is for reference only.



RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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